

# BLF7G20L-90P; BLF7G20LS-90P

Power LDMOS transistor

Rev. 01 — 28 April 2010

Product data sheet

## 1. Product profile

### 1.1 General description

90 W LDMOS power transistor for base station applications at frequencies from 1800 MHz to 2000 MHz.

**Table 1. Typical performance**

Typical RF performance at  $T_{case} = 25^\circ\text{C}$  in a common source class-AB production test circuit.

Mode of operation	f (MHz)	$I_{Dq}$ (mA)	$V_{DS}$ (V)	$P_{L(AV)}$ (W)	$G_p$ (dB)	$\eta_D$ (%)	$\text{ACPR}_{400\text{k}}$ (dBc)	$\text{ACPR}_{600\text{k}}$ (dBc)	$\text{EVM}_{\text{rms}}$ (%)
CW	1805 to 1880	550	28	84	19	54	-	-	-
GSM EDGE	1805 to 1880	550	28	40	19.5	41	-61	-74	2.5

### 1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low  $R_{th}$  providing excellent thermal stability
- Designed for broadband operation (1800 MHz to 2000 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

### 1.3 Applications

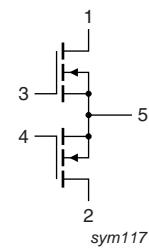
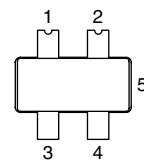
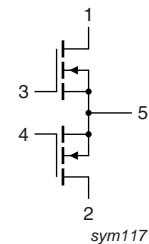
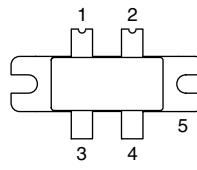
- RF power amplifiers for base stations and multi carrier applications in the 1800 MHz to 2000 MHz frequency range



## 2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
<b>BLF7G20L-90P (SOT1121A)</b>			
1	drain1		
2	drain2		
3	gate1		
4	gate2		
5	source	[1]	
<b>BLF7G20LS-90P (SOT1121B)</b>			
1	drain1		
2	drain2		
3	gate1		
4	gate2		
5	source	[1]	



[1] Connected to flange.

## 3. Ordering information

Table 3. Ordering information

Type number	Package		Version
	Name	Description	
BLF7G20L-90P	-	flanged LDMOST ceramic package; 2 mounting holes; 4 leads	SOT1121A
BLF7G20LS-90P	-	earless flanged LDMOST ceramic package; 4 leads	SOT1121B

## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage		-	65	V
$V_{GS}$	gate-source voltage		-0.5	+13	V
$I_D$	drain current		-	18	A
$T_{stg}$	storage temperature		-65	+150	°C
$T_j$	junction temperature		-	200	°C

## 5. Thermal characteristics

**Table 5. Thermal characteristics**

Symbol	Parameter	Conditions	Typ	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	$T_{case} = 80^\circ\text{C}$ ; $P_L = 90 \text{ W}$	0.49	K/W

## 6. Characteristics

**Table 6. Characteristics**

$T_j = 25^\circ\text{C}$ ; per section unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}$ ; $I_D = 0.5 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}$ ; $I_D = 50 \text{ mA}$	1.5	1.9	2.3	V
$I_{DSS}$	drain leakage current	$V_{GS} = 0 \text{ V}$ ; $V_{DS} = 28 \text{ V}$	-	-	2	$\mu\text{A}$
$I_{DSX}$	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V}$ ; $V_{DS} = 10 \text{ V}$	8.2	9.5	-	A
$I_{GSS}$	gate leakage current	$V_{GS} = 11 \text{ V}$ ; $V_{DS} = 0 \text{ V}$	-	-	200	nA
$g_f$	forward transconductance	$V_{DS} = 10 \text{ V}$ ; $I_D = 2.5 \text{ A}$	-	3.8	-	S
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V}$ ; $I_D = 1.75 \text{ A}$	-	0.28	-	$\Omega$

## 7. Test information

**Table 7. Application information**

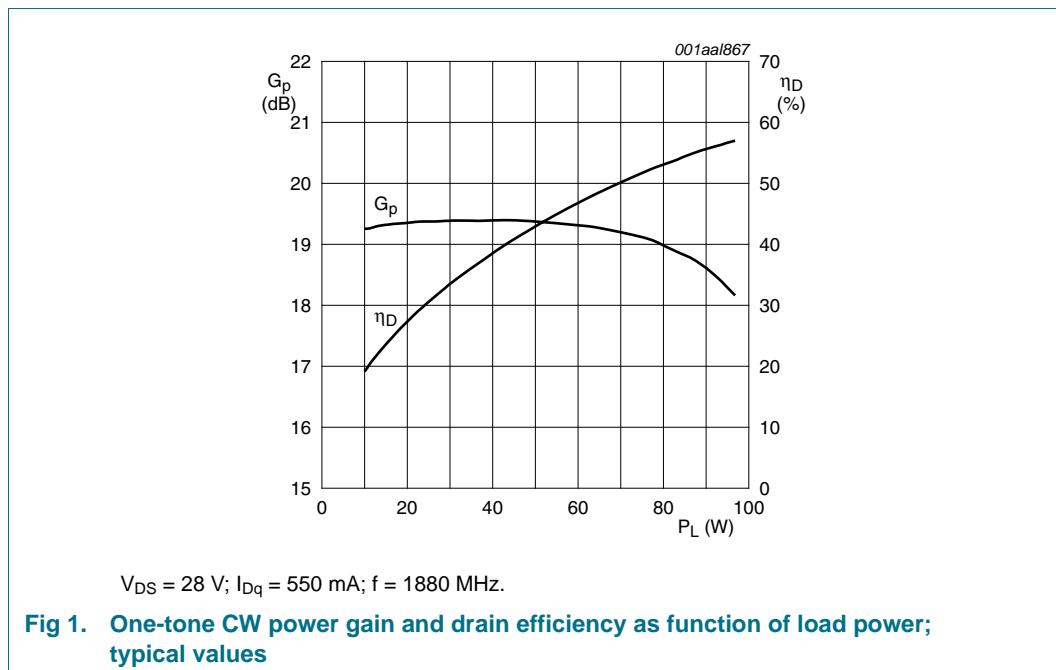
$f = 1805 \text{ MHz}$  and  $1880 \text{ MHz}$ ; RF performance at  $V_{DS} = 28 \text{ V}$ ;  $I_{Dq} = 550 \text{ mA}$ ;  $T_{case} = 25^\circ\text{C}$ ; 2 sections combined unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Mode of operation: GSM EDGE; <math>P_{L(AV)} = 40 \text{ W}</math></b>						
$G_p$	power gain		18.3	19.5	-	dB
$RL_{in}$	input return loss		-	-15	-8	dB
$\eta_D$	drain efficiency		38	41	-	%
$ACPR_{400k}$	adjacent channel power ratio (400 kHz)		-	-61	-58	dBc
$ACPR_{600k}$	adjacent channel power ratio (600 kHz)		-	-74	-70.5	dBc
$EVM_{rms}$	RMS EDGE signal distortion error		-	2.5	3.8	%
$EVM_M$	peak EDGE signal distortion error		-	8	12.5	%
<b>Mode of operation: CW; <math>P_{L(AV)} = 84 \text{ W}</math></b>						
$G_p$	power gain		17.8	19	-	dB
$\eta_D$	drain efficiency		51	54	-	%

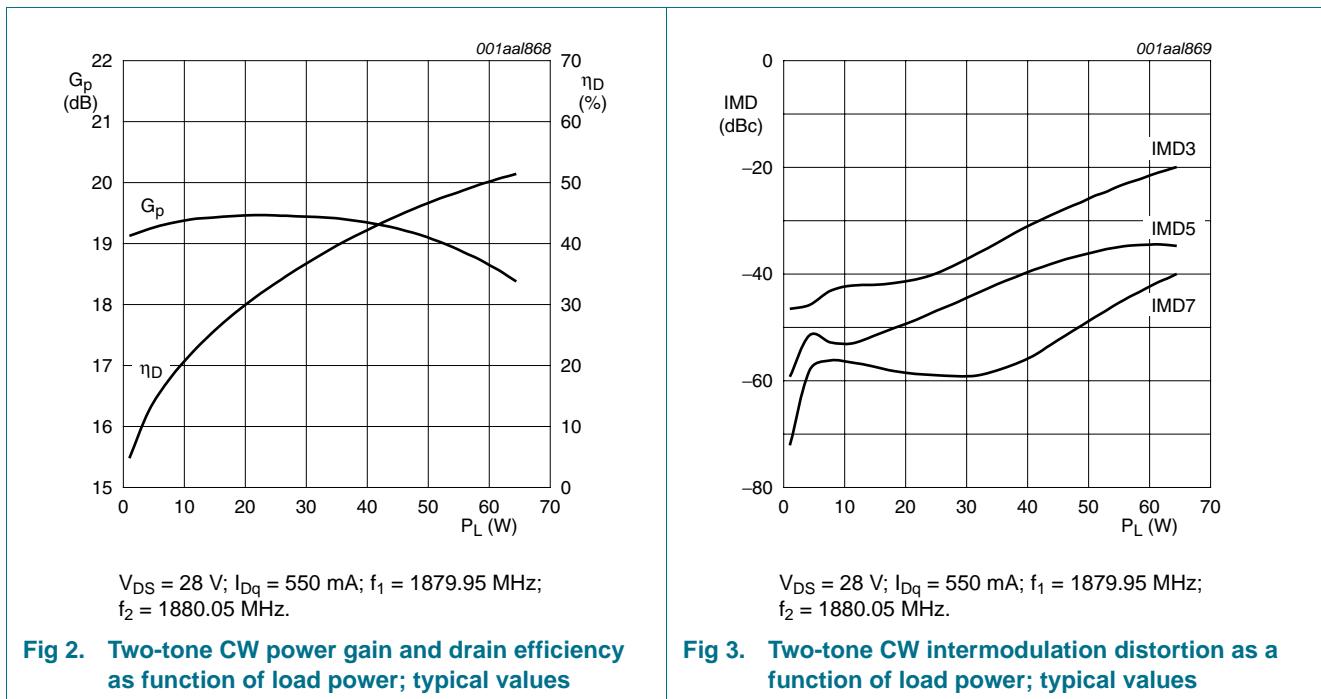
### 7.1 Ruggedness in class-AB operation

The BLF7G20L-90P and BLF7G20LS-90P are capable of withstanding a load mismatch corresponding to  $VSWR = 10 : 1$  through all phases under the following conditions:  $V_{DS} = 28 \text{ V}$ ;  $I_{Dq} = 550 \text{ mA}$ ;  $P_L = 90 \text{ W}$  (CW);  $f = 1805 \text{ MHz}$ .

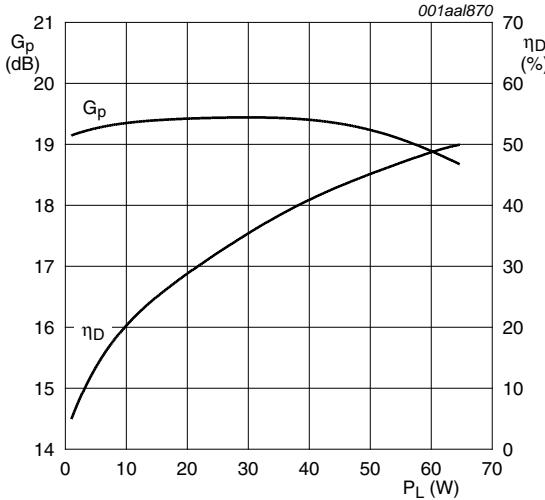
## 7.2 One-tone CW



## 7.3 Two-tone CW

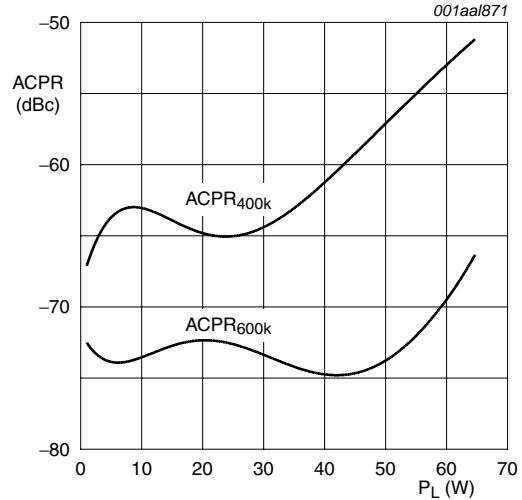


## 7.4 GSM EDGE



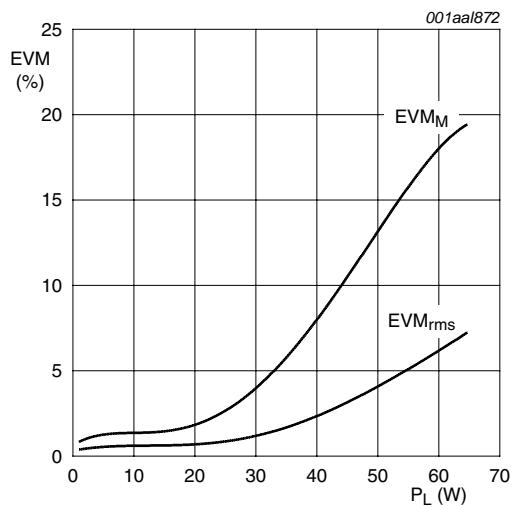
$V_{DS} = 28$  V;  $I_{Dq} = 550$  mA;  $f = 1880$  MHz.

**Fig 4. GSM EDGE power gain and drain efficiency as function of load power; typical values**



$V_{DS} = 28$  V;  $I_{Dq} = 550$  mA;  $f = 1880$  MHz.

**Fig 5. GSM EDGE ACPR at 400 kHz and at 600 kHz as function of load power; typical values**

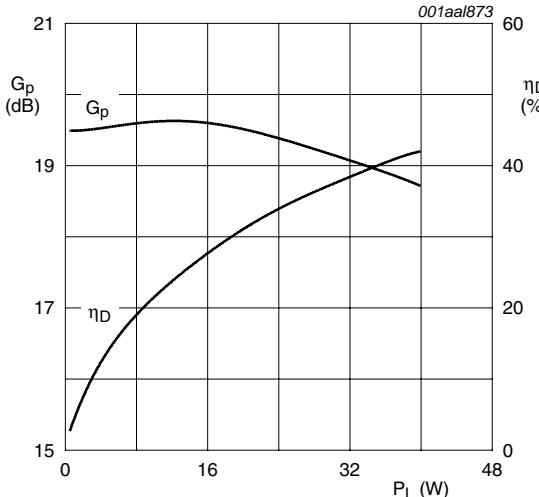


$V_{DS} = 28$  V;  $I_{Dq} = 550$  mA;  $f = 1880$  MHz.

**Fig 6. GSM-EDGE RMS EVM and peak EVM as function of load power; typical values**

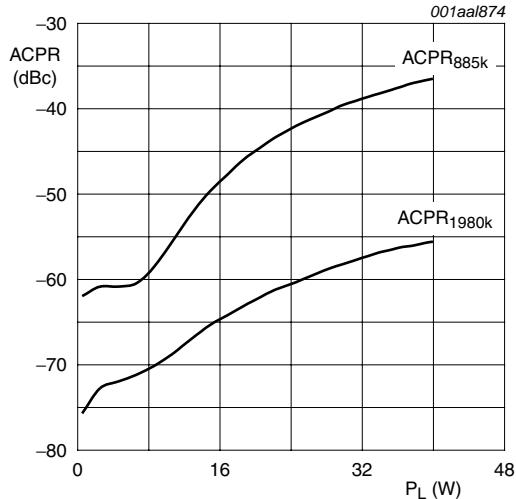
## 7.5 Single carrier IS-95

Single carrier IS-95 with pilot, paging, sync and 6 traffic channels (Walsh codes 8 - 13). PAR = 9.7 dB at 0.01 % probability on the CCDF. Channel bandwidth is 1.2288 MHz.



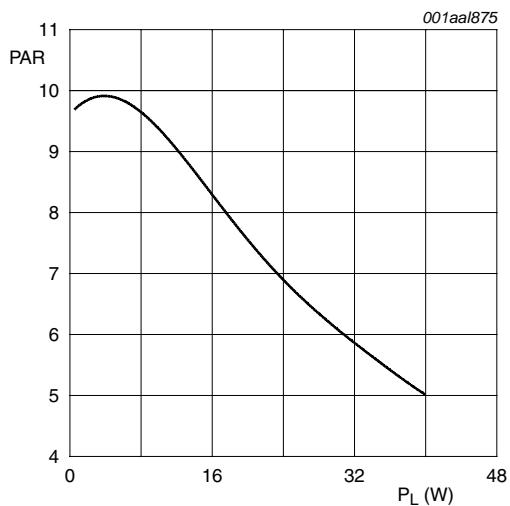
$V_{DS} = 28$  V;  $I_{DQ} = 600$  mA;  $f = 1880$  MHz.

**Fig 7. Single carrier IS-95 power gain and drain efficiency as function of load power; typical values**



$V_{DS} = 28$  V;  $I_{DQ} = 600$  mA;  $f = 1880$  MHz.

**Fig 8. Single carrier IS-95 ACPR at 885 kHz and at 1980 kHz as function of load power; typical values**

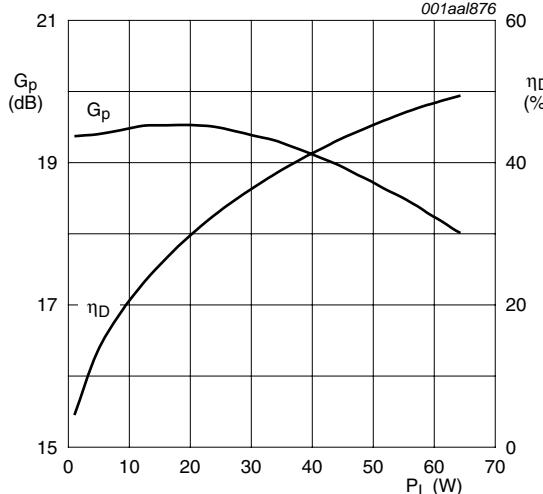


$V_{DS} = 28$  V;  $I_{DQ} = 600$  mA;  $f = 1880$  MHz.

**Fig 9. Single carrier IS-95 peak-to-average power ratio as a function of load power; typical values**

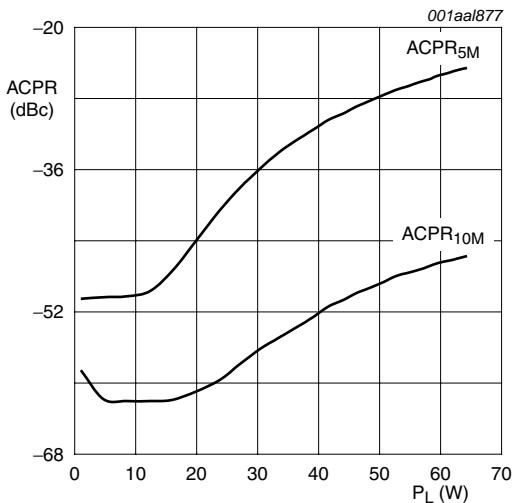
## 7.6 Single carrier W-CDMA

3GPP; test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF. Channel bandwidth is 3.84 MHz.



$V_{DS} = 28$  V;  $I_{DQ} = 600$  mA;  $f = 1880$  MHz.

**Fig 10. Single carrier W-CDMA power gain and drain efficiency as function of load power; typical values**



$V_{DS} = 28$  V;  $I_{DQ} = 600$  mA;  $f = 1880$  MHz.

**Fig 11. Single carrier W-CDMA ACPR at 5 MHz and at 10 MHz as function of load power; typical values**

## 7.7 Test circuit

**Table 8. List of components**

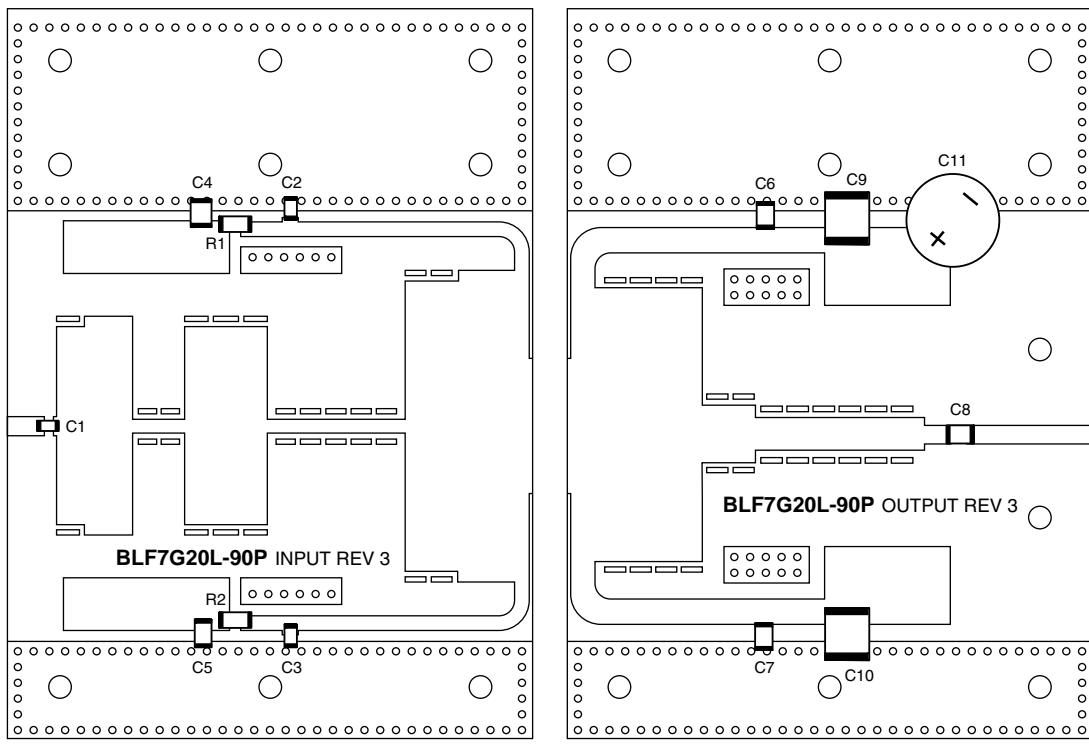
For test circuit see [Figure 12](#).

Component	Description	Value	Remarks
C1, C2, C3	multilayer ceramic chip capacitor	24 pF	[1]
C4, C5	multilayer ceramic chip capacitor	4.7 $\mu$ F	[2]
C6, C7, C8	multilayer ceramic chip capacitor	11 pF	[3]
C9, C10	multilayer ceramic chip capacitor	10 $\mu$ F	[2]
C11	electrolytic capacitor	470 $\mu$ F; 63 V	
R1, R2	SMD resistor	12 $\Omega$	Philips 1206

[1] American Technical Ceramics type 100A or capacitor of same quality.

[2] TDK or capacitor of same quality.

[3] American Technical Ceramics type 100B or capacitor of same quality.



Printed-Circuit Board (PCB): Taconic RF35;  $\epsilon_r = 3.5$  F/m; thickness = 0.76 mm; thickness copper plating = 35  $\mu\text{m}$ .

See [Table 8](#) for a list of components.

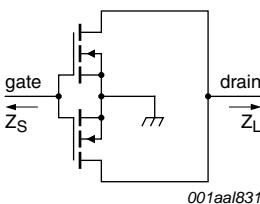
**Fig 12. Component layout for class-AB production test circuit**

## 7.8 Impedance information

**Table 9. Typical impedance**

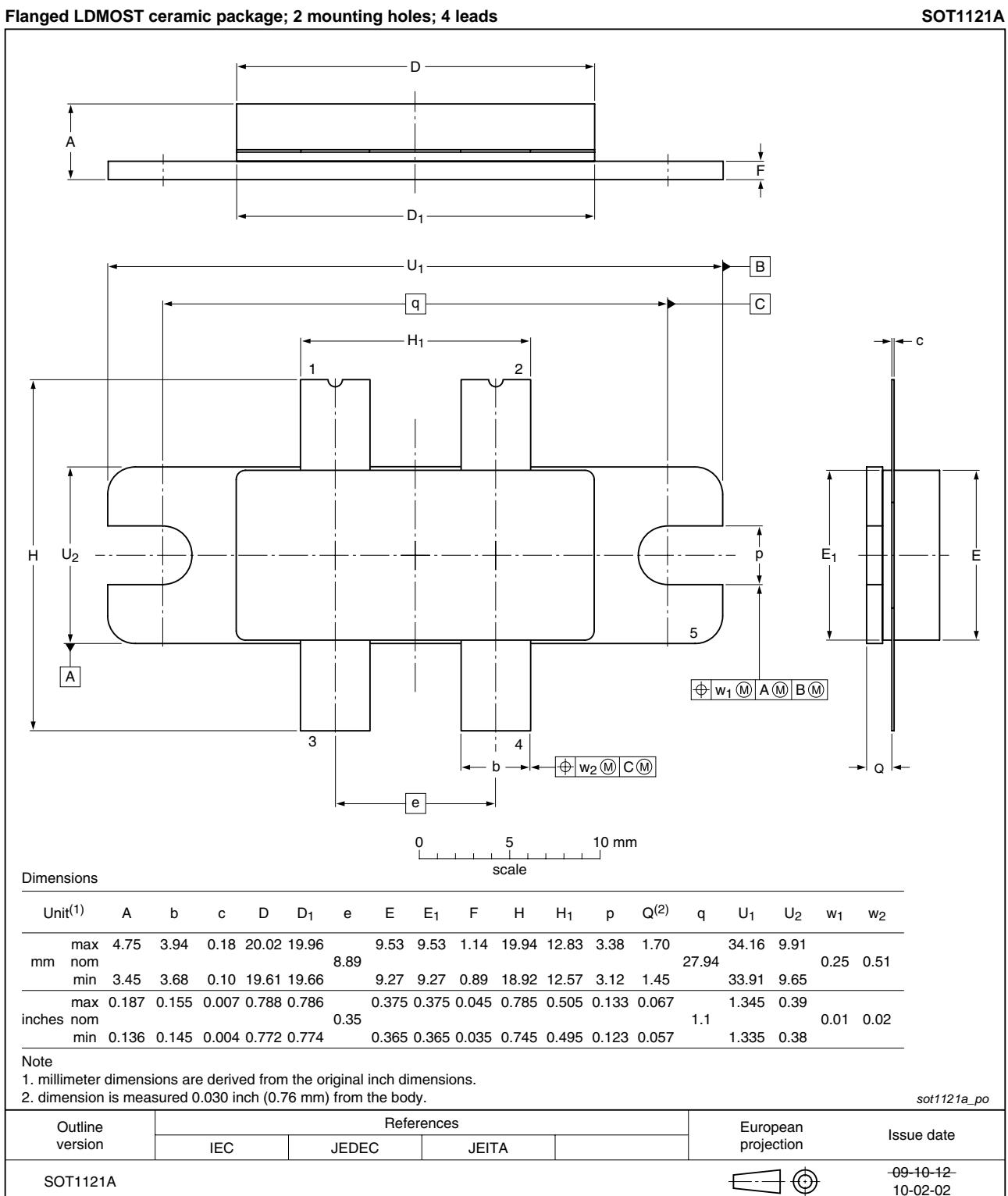
Typical values valid for both section in parallel unless otherwise specified.

f MHz	$Z_S$ $\Omega$	$Z_L$ $\Omega$
1800	1.0 – j3.3	2.8 – j2.7
1840	1.2 – j3.3	2.8 – j2.5
1880	1.1 – j3.4	2.7 – j2.4



**Fig 13. Definition of transistor impedance**

## 8. Package outline



**Fig 14. Package outline SOT1121A**

## Earless flanged LDMOST ceramic package; 4 leads

SOT1121B

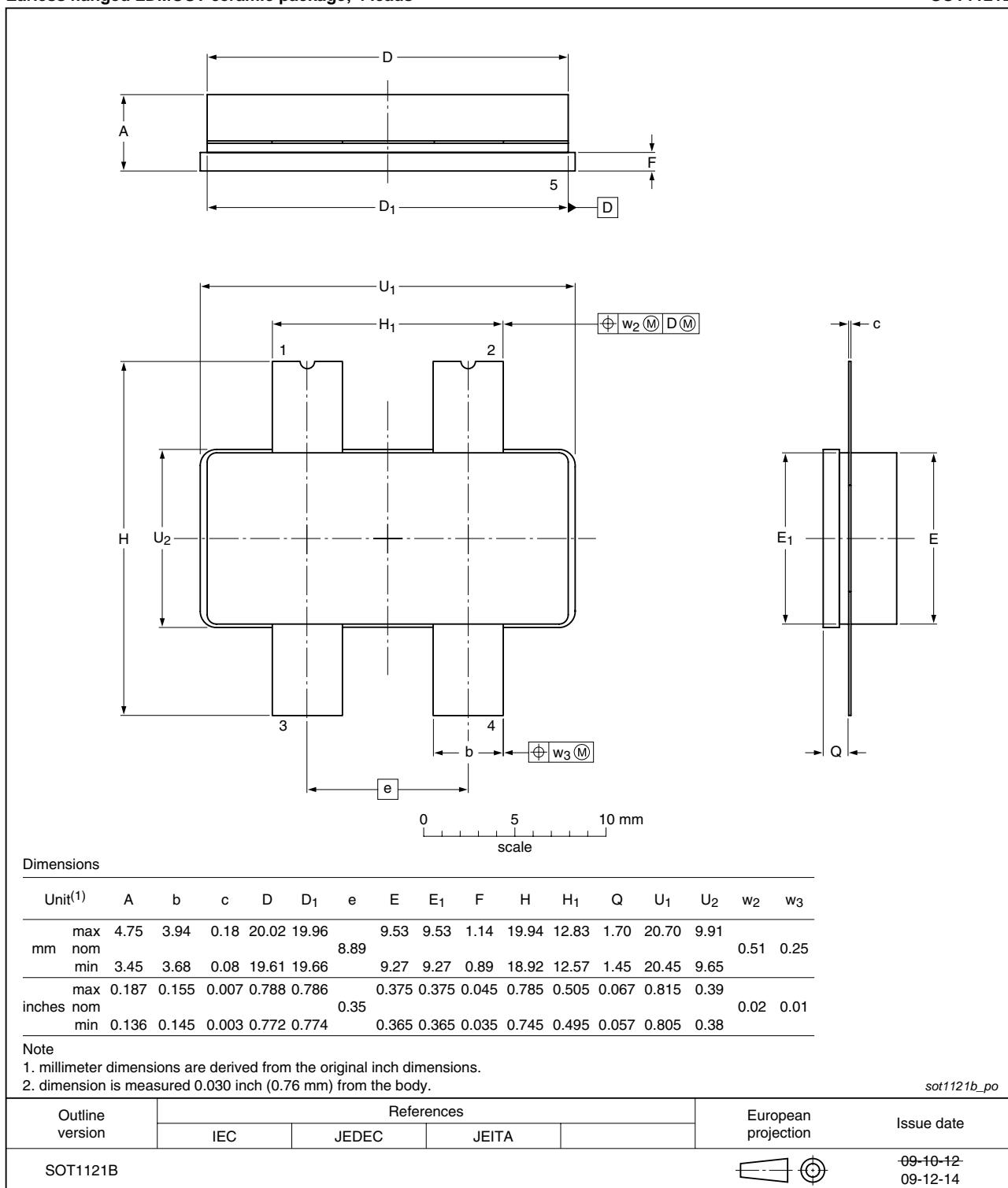


Fig 15. Package outline SOT1121B

## 9. Abbreviations

**Table 10. Abbreviations**

Acronym	Description
3GPP	3rd Generation Partnership Project
CW	Continuous Wave
EDGE	Enhanced Data rates for GSM Evolution
ESD	ElectroStatic Discharge
IS-95	Interim Standard 95
LDMOS	Laterally Diffused Metal Oxide Semiconductor
LDMOST	Laterally Diffused Metal Oxide Semiconductor Transistor
RF	Radio Frequency
SMD	Surface Mounted Device
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

## 10. Revision history

**Table 11. Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF7G20L-90P_7G20LS-90P_1	20100428	Product data sheet	-	-

## 11. Legal information

### 11.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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